

Schedule of Scope to Certificate of Approval

Independent Testing Laboratory

IECQ Certificate No.: IECQ-L CEP 20.0001 CB Certificate No.: IECQ-L 2020.001

Schedule Number: IECQ-L CEP 20.0001-S Rev No.: 5 Revision Date: 2024/10/23 Page 1 of 20

Nº	Nº Products, Materials		Items, Parameter	Title, Code of specification, standard or method used
			Items, Parameter	standard or method used
		1	Visual inspection (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
1	1 Integrated Circuits	5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		6	Biased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
			Unbiased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		8	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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Schedule Number: IECQ-L CEP 20.0001-S Rev No.: 5 Revision Date: 2024/10/23 Page 2 of 20 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 9 Power Temperature Cycling IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 10 High Temperature Storage Life IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS High Temperature Operating 11 IN AUTOMOTIVE APPLICATIONS Life AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS 12 Early Life Failure Rate IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST **QUALIFICAION FOR INTEGRATED CIRCUITS** 13 Wire Bond Shear IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 14 Wire Bond Pull IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 15 Solderability IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 16 Physical Dimensions IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 17 Solder Ball Shear IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS Pre- and Post-Stress 18 Function/Parameter IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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Schedule Number: IECQ-L CEP 20.0001-S Rev No.: 5 Revision Date: 2024/10/23 Page 3 of 20 FAILURE MECHANISM BASED STRESS TEST Electrostatic Discharge Human QUALIFICAION FOR INTEGRATED CIRCUITS 19 Body Model IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST Electrostatic Discharge Charged QUALIFICAION FOR INTEGRATED CIRCUITS 20 Device Model IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS 21 Mechanical Shock IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST **QUALIFICAION FOR INTEGRATED CIRCUITS** 22 Variable Frequency Vibration IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 23 Constant Acceleration IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 24 Gross/Fine Leak IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 25 Package Drop IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 26 Die Shear IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 27 Internal Water Vapor IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE Discrete Visual inspection (Pre-2 1 SEMICONDUCTORS IN AUTOMOTIVE Semiconductors conditioning) APPLICATIONS AEC-Q101-Rev-E March 1,2021

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2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
6	Highly Accelerated Stress Test	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
7	High Humidity High Temp. Reverse Bias	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
8	Unbiased HAST	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
9	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021

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			FAILURE MECHANISM BASED S	TRESS TEST
			QUALIFICAION FOR DISC	
	10	Temperature Cycling Hot Test	SEMICONDUCTORS IN AUTO	
			APPLICATIONS	
			AEC-Q101-Rev-E March 1	.2021
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR DISC	CRETE
	11	Power Temperature Cycling	SEMICONDUCTORS IN AUTO	OMOTIVE
		1 7 8	APPLICATIONS	
			AEC-Q101-Rev-E March 1	2021
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR DISC	
	12	Physical Dimension	SEMICONDUCTORS IN AUTO	
		5	APPLICATIONS	
			AEC-Q101-Rev-E March 1	,2021
			FAILURE MECHANISM BASED S	TRESS TEST
			QUALIFICAION FOR DISC	
	13	Wire Bond Pull Strength	SEMICONDUCTORS IN AUTO	OMOTIVE
		C C	APPLICATIONS	
			AEC-Q101-Rev-E March 1	,2021
			FAILURE MECHANISM BASED S	TRESS TEST
			QUALIFICAION FOR DISC	CRETE
	14	Wire Bond Shear Strength	SEMICONDUCTORS IN AUTO	OMOTIVE
		_	APPLICATIONS	
			AEC-Q101-Rev-E March 1	,2021
			FAILURE MECHANISM BASED S	TRESS TEST
			QUALIFICAION FOR DISC	CRETE
	15	Die Shear	SEMICONDUCTORS IN AUTO	OMOTIVE
			APPLICATIONS	
			AEC-Q101-Rev-E March 1	
			FAILURE MECHANISM BASED S	
	16	Resistance to Solder Heat	QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO	
	10	Resistance to Solder Heat	APPLICATIONS	
			AEC-Q101-Rev-E March 1	.2021
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR DISC	
	17	Thermal Resistance	SEMICONDUCTORS IN AUTO	
			APPLICATIONS	
			AEC-Q101-Rev-E March 1	2021

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			FAILURE MECHANISM BASED S QUALIFICAION FOR DISC	
	18	Solderability	SEMICONDUCTORS IN AUTO APPLICATIONS	DMOTIVE
			AEC-Q101-Rev-E March 1	-
	19	Constant Acceleration	FAILURE MECHANISM BASED S QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO APPLICATIONS	CRETE
			AEC-Q101-Rev-E March 1	,2021
	20	Vibration Variable Frequency	FAILURE MECHANISM BASED S QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q101-Rev-E March 1	CRETE DMOTIVE
	21	Mechanical Shock	FAILURE MECHANISM BASED S QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO APPLICATIONS	CRETE
			AEC-Q101-Rev-E March 1	,2021
	22	Hermeticity	FAILURE MECHANISM BASED S QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q101-Rev-E March 1	CRETE DMOTIVE
	23	External Visual	FAILURE MECHANISM BASED S QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q101-Rev-E March 1	STRESS TEST CRETE DMOTIVE
	24	Pre- and Post-Stress Electrical Test	FAILURE MECHANISM BASED S	STRESS TEST CRETE DMOTIVE
	25	Parametric Verification	FAILURE MECHANISM BASED S QUALIFICAION FOR DISC SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q101-Rev-E March 1	STRESS TEST CRETE DMOTIVE

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		26	ESD HBM Characterization	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS
		27	ESD CDM Characterization	AEC-Q101-Rev-E March 1,2021 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR DISCRETE SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q101-Rev-E March 1,2021
	3 Optoelectronic Semiconductors	1	Visual inspection (Pre- conditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		2	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
3		3	Bake out (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		4	Moisture Soak (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		5	Reflow (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020
		6	Wet High Temperature Operating Life1	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC SEMICONDUCTORS IN AUTOMOTIVE APPLICATIONS AEC-Q102-Rev-A April 6,2020

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	7	Wet High Temperature Operating Life2	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOEL SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	ECTRONIC DMOTIVE
	8	High Humidity High Temperature Reverse Bias	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOELI SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	STRESS TEST ECTRONIC DMOTIVE
	9	Power Temperature Cycling	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOEL SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	ECTRONIC DMOTIVE
	10	Temperature Cycling	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOEL SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	STRESS TEST ECTRONIC DMOTIVE
	11	High Temperature Operating Life 1	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOELI SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	STRESS TEST ECTRONIC DMOTIVE
	12	High Temperature Operating Life 2	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOELI SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	STRESS TEST ECTRONIC DMOTIVE
	13	Low Temperature Operating Life	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOEL	STRESS TEST ECTRONIC DMOTIVE
	14	Physical Dimension	FAILURE MECHANISM BASED S QUALIFICAION FOR OPTOELI SEMICONDUCTORS IN AUTO APPLICATIONS AEC-Q102-Rev-A April 6,	STRESS TEST ECTRONIC DMOTIVE

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			FAILURE MECHANISM BASED S	STRESS TEST
	15	Wire Bond Pull	QUALIFICAION FOR OPTOELI SEMICONDUCTORS IN AUTO	
		Whe Dona I an	APPLICATIONS	
			AEC-Q102-Rev-A April 6,	2020
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR OPTOELI	
	16	Wire Bond Shear	SEMICONDUCTORS IN AUTO	
			APPLICATIONS	
			AEC-Q102-Rev-A April 6,	2020
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR OPTOELI	
	17	Die Shear	SEMICONDUCTORS IN AUTO	
			APPLICATIONS	
			AEC-Q102-Rev-A April 6,	2020
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR OPTOELI	
	18	Resistance to Solder Heat	SEMICONDUCTORS IN AUTO	
			APPLICATIONS	
			AEC-Q102-Rev-A April 6,	2020
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR OPTOELI	ECTRONIC
	19	Solderability	SEMICONDUCTORS IN AUTO	OMOTIVE
			APPLICATIONS	
			AEC-Q102-Rev-A April 6,	2020
			FAILURE MECHANISM BASED S	STRESS TEST
			QUALIFICAION FOR OPTOELI	ECTRONIC
	20	External Visual	SEMICONDUCTORS IN AUTO	DMOTIVE
			APPLICATIONS	
			AEC-Q102-Rev-A April 6,	
			FAILURE MECHANISM BASED S	
	21	Electrostatic Discharge Human	QUALIFICAION FOR OPTOELI SEMICONDUCTORS IN AUTO	
	21	Body Model	APPLICATIONS	JNIO II V E
			AEC-Q102-Rev-A April 6,	2020
			FAILURE MECHANISM BASED S	
			OUALIFICATON FOR OPTOFU	
	22	Electrostatic Discharge Charged	SEMICONDUCTORS IN AUTO	
		Device Model	APPLICATIONS	-
			AEC-Q102-Rev-A April 6,	2020

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				FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR OPTOELECTRONIC
		23	Constant Acceleration	SEMICONDUCTORS IN AUTOMOTIVE
				APPLICATIONS
				AEC-Q102-Rev-A April 6,2020
				FAILURE MECHANISM BASED STRESS TEST
				QUALIFICAION FOR OPTOELECTRONIC
		24	Vibration Variable Frequency	SEMICONDUCTORS IN AUTOMOTIVE
				APPLICATIONS
				AEC-Q102-Rev-A April 6,2020
				FAILURE MECHANISM BASED STRESS TEST
				QUALIFICAION FOR OPTOELECTRONIC
		25	Mechanical Shock	SEMICONDUCTORS IN AUTOMOTIVE
				APPLICATIONS
				AEC-Q102-Rev-A April 6,2020
			Hermeticity	FAILURE MECHANISM BASED STRESS TEST
		26		QUALIFICAION FOR OPTOELECTRONIC
				SEMICONDUCTORS IN AUTOMOTIVE
				APPLICATIONS
				AEC-Q102-Rev-A April 6,2020
				FAILURE MECHANISM BASED STRESS TEST
			Visual inspection	QUALIFICAION FOR MULTICHIP
		1	(Preconditioning)	MODULES(MCM) IN AUTOMOTIVE
				APPLICATIONS
				AEC-Q104-REV-September 14, 2017
		2		FAILURE MECHANISM BASED STRESS TEST
			Temperature cycling (Preconditioning)	QUALIFICAION FOR MULTICHIP
				MODULES(MCM) IN AUTOMOTIVE
	Multichip Modules		(Treconditioning)	APPLICATIONS
4	(MCM)			AEC-Q104-REV-September 14, 2017
	(FAILURE MECHANISM BASED STRESS TEST
				QUALIFICAION FOR MULTICHIP
		3	Bake out (Preconditioning)	MODULES(MCM) IN AUTOMOTIVE
				APPLICATIONS
				AEC-Q104-REV-September 14, 2017
				FAILURE MECHANISM BASED STRESS TEST
		4	Moisture Soak	QUALIFICAION FOR MULTICHIP
		-	(Preconditioning)	MODULES(MCM) IN AUTOMOTIVE
				APPLICATIONS

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		AEC-Q104-REV-September 14, 2017
		FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
5	Reflow (Preconditioning)	MODULES(MCM) IN AUTOMOTIVE
		APPLICATIONS
		AEC-Q104-REV-September 14, 2017
		FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
6	Biased HAST	MODULES(MCM) IN AUTOMOTIVE
		APPLICATIONS
		AEC-Q104-REV-September 14, 2017
		FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
7	Unbiased HAST	MODULES(MCM) IN AUTOMOTIVE
		APPLICATIONS
		AEC-Q104-REV-September 14, 2017
	Temperature Cycling	FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
8		MODULES(MCM) IN AUTOMOTIVE
		APPLICATIONS
		AEC-Q104-REV-September 14, 2017
		FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
9	Power Temperature Cycling	MODULES(MCM) IN AUTOMOTIVE
		APPLICATIONS
		AEC-Q104-REV-September 14, 2017
		FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
10	High Temperature Storage Life	MODULES(MCM) IN AUTOMOTIVE
		APPLICATIONS
		AEC-Q104-REV-September 14, 2017
		FAILURE MECHANISM BASED STRESS TEST
		QUALIFICAION FOR MULTICHIP
11	High Temperature Operating	MODULES(MCM) IN AUTOMOTIVE
	Life	APPLICATIONS
		AEC-Q104-REV-September 14, 2017

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Independent Testing Laboratory

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			FAILURE MECHANISM BASED S	TDECC TECT
			QUALIFICAION FOR MUL	
	2	Early Life Failure Rate		
	12	Early Life Failure Rate	MODULES(MCM) IN AUTO APPLICATIONS	MOTIVE
			AEC-Q104-REV-September 14	4 2017
			FAILURE MECHANISM BASED S	
	3	Wire Bond Shear	QUALIFICAION FOR MUL	
		whe bond shear	MODULES(MCM) IN AUTON APPLICATIONS	MOTIVE
				4 2017
			AEC-Q104-REV-September 1	
			FAILURE MECHANISM BASED S	
	4	W D 1 D-11	QUALIFICAION FOR MUL	
	4	Wire Bond Pull	MODULES(MCM) IN AUTON	MOTIVE
			APPLICATIONS	4 2017
			AEC-Q104-REV-September 1-	
		Solderability MCM External Leads	FAILURE MECHANISM BASED S	
	5		QUALIFICAION FOR MUL	
	15		MODULES(MCM) IN AUTON	MOTIVE
			APPLICATIONS	4 2015
			AEC-Q104-REV-September 1	
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR MUL	
	6	Physical Dimensions	MODULES(MCM) IN AUTON	MOTIVE
			APPLICATIONS	
			AEC-Q104-REV-September 1	
			FAILURE MECHANISM BASED S	
	7	Solder Ball Shear	QUALIFICAION FOR MUL	
		Solder Ball Shear	MODULES(MCM) IN AUTO APPLICATIONS	MOTIVE
			AEC-Q104-REV-September 14	4. 2017
			FAILURE MECHANISM BASED S	
			QUALIFICAION FOR MUL	
1	8	X-Ray	MODULES(MCM) IN AUTO	MOTIVE
			APPLICATIONS	
			AEC-Q104-REV-September 14	4, 2017
			FAILURE MECHANISM BASED S	STRESS TEST
			QUALIFICAION FOR MUL	TICHIP
	9	Acoustic Microscopy	MODULES(MCM) IN AUTON	MOTIVE
			APPLICATIONS	
			AEC-Q104-REV-September 14	4, 2017

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	20	Pre- and Post-Stress Function/Parameter	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	TICHIP MOTIVE
	21	Electrostatic Discharge Human Body Model	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTOI APPLICATIONS AEC-Q104-REV-September 1	STRESS TEST TICHIP MOTIVE
	22	Electrostatic Discharge Charged Device Model	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	STRESS TEST TICHIP MOTIVE
	23	Mechanical Shock	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	STRESS TEST TICHIP MOTIVE
	24	Variable Frequency Vibration	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	TICHIP MOTIVE
	25	Constant Acceleration	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	STRESS TEST TICHIP MOTIVE
	26	Gross/Fine Leak	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	TICHIP MOTIVE
	27	Mechanical Shock Cavity Device Drop	FAILURE MECHANISM BASED S QUALIFICAION FOR MUL MODULES(MCM) IN AUTO APPLICATIONS AEC-Q104-REV-September 1	TICHIP MOTIVE

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				FAILURE MECHANISM BASED S	TDESS TEST
		28	Die Shear	QUALIFICAION FOR MUL MODULES(MCM) IN AUTON	
		20	Die Silear	APPLICATIONS	NOTIVE
				AEC-Q104-REV-September 14	1 2017
				FAILURE MECHANISM BASED S	
		29	Internal Water Vener	QUALIFICAION FOR MUL	
		29	Internal Water Vapor	MODULES(MCM) IN AUTOM APPLICATIONS	NOTIVE
					4 2017
				AEC-Q104-REV-September 14	
				FAILURE MECHANISM BASED S	
		30		QUALIFICAION FOR MUL	
		30	Low Temperature Storage Life	MODULES(MCM) IN AUTON	MOTIVE
				APPLICATIONS	1 2017
				AEC-Q104-REV-September 14	
			FA	FAILURE MECHANISM BASED S	
		21		QUALIFICAION FOR MULTIC	
		31	MCM Drop Test	MODULES(MCM) IN AUTON	MOTIVE
				APPLICATIONS	
				AEC-Q104-REV-September 14	
				FAILURE MECHANISM BASED S	
		22		QUALIFICAION FOR MUL	
		32	X-ray	MODULES(MCM) IN AUTON	MOTIVE
				APPLICATIONS	
				AEC-Q104-REV-September 14	
			Acoustic Microscopy	FAILURE MECHANISM BASED S	
		22		QUALIFICAION FOR MUL	
		33		MODULES(MCM) IN AUTON	MOTIVE
				APPLICATIONS	
				AEC-Q104-REV-September 14	
	Passive 2 components 3		Pre-and Post-Stress Electrical Test	STRESS TEST QUALIFICATION F	OR PASSIVE
				COMPONENTS	1.0
				AEC-Q200 REV D June 1, 2010 Tal	
5		2		STRESS TEST QUALIFICATION F	OR PASSIVE
		<u> </u>	High Temperature Exposure	COMPONENTS	
				AEC-Q200 REV D June 1, 2010 Tal	
		3		STRESS TEST QUALIFICATION F	OR PASSIVE
		5	Temperature Cycling	COMPONENTS	
				AEC-Q200 REV D June 1, 2010 Tal	ole2~ Table14

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	4	Destructive Physical Analysis	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
	5	Moisture Resistance	STRESS TEST QUALIFICATION FOR PASSIVE
	5		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
	6	Humidity Bias	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
	7	7 High Temperature Operating Life	STRESS TEST QUALIFICATION FOR PASSIVE
	,		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
	0		STRESS TEST QUALIFICATION FOR PASSIVE
	8	External Visual	COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
		Physical Dimensions	STRESS TEST QUALIFICATION FOR PASSIVE
	9		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
		Terminal Strength	STRESS TEST QUALIFICATION FOR PASSIVE
	10		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
		Resistance to Solvent	STRESS TEST QUALIFICATION FOR PASSIVE
	11		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
			STRESS TEST QUALIFICATION FOR PASSIVE
	12	Mechanical Shock	COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
		Vibration	STRESS TEST QUALIFICATION FOR PASSIVE
	13		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
		Resistance to Solder	STRESS TEST QUALIFICATION FOR PASSIVE
	14	Heat	COMPONENTS
		Iteat	AEC-Q200 REV D June 1, 2010 Table2~ Table14
		Thermal Shock	STRESS TEST QUALIFICATION FOR PASSIVE
	15		COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14
			STRESS TEST QUALIFICATION FOR PASSIVE
	16	ESD	COMPONENTS
			AEC-Q200 REV D June 1, 2010 Table2~ Table14

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 STRESS TEST QUALIFICATION FOR PASSIVE

17	Solderability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
18	Electrical Characterization	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
19	Flammability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
20	Board Flex	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
21	Terminal Strength (SMD)	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
22	Beam Load	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
23	Flame Retardance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
24	Rotation Life	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
25	Surge Voltage	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
26	Salt Spray	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
27	Shear Strength	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
28	Short Circuit Fault Current Durability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
29	Fault Current Durability	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14

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		30	End-of-Life Mode Verification	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		31	Jump Start Endurance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
		32	Load Dump Endurance	STRESS TEST QUALIFICATION FOR PASSIVE COMPONENTS AEC-Q200 REV D June 1, 2010 Table2~ Table14
Micro Electro- Mechanical 6 System(MEMS) Pressure Sensor Devices	1	PrHTOL	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019	
	2	PrLTOL	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019	
	Mechanical System(MEMS)	3	BPr	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-Q103-002 REV D March 1, 2019
		4	PPr	FAILURE MECHANISM BASED STRESS TEST QUALIFICATION FOR MICRO ELECTRO-MECHANICAL SYSTEM(MEMS) PRESSURE SENSOR DEVICES AEC-0103-002 REV D March 1, 2019
		5	Visual inspection (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023
		6	Temperature cycling (Preconditioning)	FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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Schedule Number: IECQ-L CEP 20.0001-S Rev No.: 5 Revision Date: 2024/10/23 Page 18 of 20 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 7 Bake out (Preconditioning) IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST Moisture Soak QUALIFICAION FOR INTEGRATED CIRCUITS 8 (Preconditioning) IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS 9 Reflow (Preconditioning) IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS 10 Biased HAST IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST **QUALIFICAION FOR INTEGRATED CIRCUITS** 11 Unbiased HAST IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 12 Temperature Cycling IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 13 Power Temperature Cycling IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 14 High Temperature Storage Life IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST High Temperature Operating QUALIFICAION FOR INTEGRATED CIRCUITS 15 IN AUTOMOTIVE APPLICATIONS Life AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 16 Early Life Failure Rate IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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Schedule Number: IECQ-L CEP 20.0001-S Rev No.: 5 Revision Date: 2024/10/23 Page 19 of 20 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 17 Wire Bond Shear IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 18 Wire Bond Pull IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS 19 Solderability IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST OUALIFICAION FOR INTEGRATED CIRCUITS 20 Physical Dimensions IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST **QUALIFICAION FOR INTEGRATED CIRCUITS** 21 Solder Ball Shear IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST Pre- and Post-Stress QUALIFICAION FOR INTEGRATED CIRCUITS 22 Function/Parameter IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST Electrostatic Discharge Human QUALIFICAION FOR INTEGRATED CIRCUITS 23 Body Model IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST Electrostatic Discharge Charged QUALIFICAION FOR INTEGRATED CIRCUITS 24 IN AUTOMOTIVE APPLICATIONS Device Model AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 25 Mechanical Shock IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023 FAILURE MECHANISM BASED STRESS TEST QUALIFICAION FOR INTEGRATED CIRCUITS 26 Variable Frequency Vibration IN AUTOMOTIVE APPLICATIONS AEC-Q100-REV-J August 11.2023

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		FAILURE MECHANISM BASED STRESS TEST
27	Constant Acceleration	QUALIFICAION FOR INTEGRATED CIRCUITS
2,	Constant Acceleration	IN AUTOMOTIVE APPLICATIONS
		AEC-Q100-REV-J August 11.2023
		FAILURE MECHANISM BASED STRESS TEST
28	Gross/Fine Leak	QUALIFICAION FOR INTEGRATED CIRCUITS
20	Gross/Time Leak	IN AUTOMOTIVE APPLICATIONS
		AEC-Q100-REV-J August 11.2023
		FAILURE MECHANISM BASED STRESS TEST
29	Dealrage Drow	QUALIFICAION FOR INTEGRATED CIRCUITS
29	Package Drop	IN AUTOMOTIVE APPLICATIONS
		AEC-Q100-REV-J August 11.2023
		FAILURE MECHANISM BASED STRESS TEST
30	Die Shear	QUALIFICAION FOR INTEGRATED CIRCUITS
50	Die Silear	IN AUTOMOTIVE APPLICATIONS
		AEC-Q100-REV-J August 11.2023
		FAILURE MECHANISM BASED STRESS TEST
31		QUALIFICAION FOR INTEGRATED CIRCUITS
51	Internal Water Vapor	IN AUTOMOTIVE APPLICATIONS
		AEC-Q100-REV-J August 11.2023

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